



4-28-03

2673 #3

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

1<sup>st</sup> Named Inventor: EKKEL, Frederik  
Application No.: 10/004,049 Conf.:  
Date Filed: 10/02/2000

Docket No.: US01 8177  
Art Unit: 2673  
Examiner: Unknown

Title: A System & Method To Enhance Manufacturing Test Failure Analysis with Dedicated Pins

RECEIVED

APR 29 2003

Assistant Commissioner for Patents  
Washington, D.C. 20231

Technology Center 2600

## LETTER

Sir:

Applicant(s) calls to the attention of the Patent and Trademark Office a Search Report issued abroad in reference to a corresponding foreign application. A copy of the Search Report dated 02/11/2003 is attached.

An Information Disclosure Statement under 37 CFR 1.56 is not being filed because the Search Report indicates only "A" references, which the Search Report states are "documents defining the general state of the art which is not considered of particular relevance". The enclosed Search Report is not intended to be construed as an admission by the Applicant(s) that any of the references cited therein is material.

Respectfully submitted,

Date:

4/24/03

By

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Encl. Search Report

## CERTIFICATE OF MAILING OR TRANSMISSION

I hereby certify that on the date indicated below this correspondence is being:

☒ deposited with the U.S. Postal Service with sufficient postage for first class mail in an envelope addressed to "Asst. Commissioner for Patents, Washington, D.C. 20231".

☐ transmitted by facsimile to the USPTO at 703

04.24.03

Date

Daniel L. Michalek